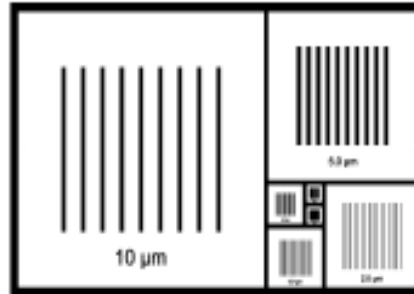
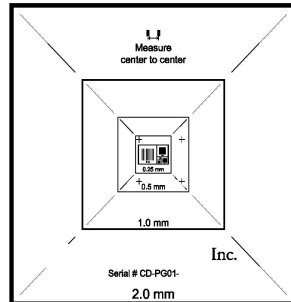


Wafer Level Certificate of Traceability for Critical Dimension Standard Pelcotec™ CDMS- 0.1T, 2mm - 100nm, Traceable



Product Number: 683-01 and 683-01A through 683-01Z

Product Description: 2.5x2.5mm Critical Dimension Magnification Standard

Wafer Identifier: CD-UC01

The accuracy of these products was determined by reference comparison to working standards traceable to the National Institute of Standards and Technology (NIST), Test No. 861/280822-11.

Line	Average pitch of wafer	Number of lines averaged	Average pitch uniformity (1 σ uncertainty)	Total expanded uncertainty (3 σ) average pitch for wafer*
2.0mm	2.00mm	2	$\pm 2\mu\text{m}$ ($\pm 0.10\%$)	$\pm 7\mu\text{m}$ ($\pm 0.35\%$)
1.0mm	1.00mm	2	$\pm 1\mu\text{m}$ ($\pm 0.10\%$)	$\pm 3.5\mu\text{m}$ ($\pm 0.35\%$)
0.5mm	0.500mm	2	$\pm 0.5\mu\text{m}$ ($\pm 0.10\%$)	$\pm 1.75\mu\text{m}$ ($\pm 0.35\%$)
0.25mm	0.250mm	2	$\pm 0.25\mu\text{m}$ ($\pm 0.10\%$)	$\pm 0.9\mu\text{m}$ ($\pm 0.35\%$)
10 μm	10.00 μm	9	$\pm 0.01\mu\text{m}$ ($\pm 0.10\%$)	$\pm 0.035\mu\text{m}$ ($\pm 0.35\%$)
5 μm	5.00 μm	12	$\pm 0.01\mu\text{m}$ ($\pm 0.20\%$)	$\pm 0.035\mu\text{m}$ ($\pm 0.70\%$)
2 μm	2.00 μm	10	$\pm 0.004\mu\text{m}$ ($\pm 0.20\%$)	$\pm 0.014\mu\text{m}$ ($\pm 0.70\%$)
1 μm	1.00 μm	10	$\pm 0.002\mu\text{m}$ ($\pm 0.20\%$)	$\pm 0.007\mu\text{m}$ ($\pm 0.70\%$)
500nm	500.6nm	10	$\pm 1.00\text{nm}$ ($\pm 0.20\%$)	$\pm 3.5\text{nm}$ ($\pm 0.70\%$)
250nm	249.9nm	10	$\pm 0.50\text{nm}$ ($\pm 0.20\%$)	$\pm 1.75\text{nm}$ ($\pm 0.70\%$)
100nm	100.1nm	10	$\pm 0.20\text{nm}$ ($\pm 0.20\%$)	$\pm 0.75\text{nm}$ ($\pm 0.70\%$)

* The 3 σ uncertainty (95% confidence interval) average pitch is determined using a minimum of nine die per production wafer. Each average pitch is determined using 100+ measurements on each die averaged over the stated number of lines. The total expanded uncertainty includes both Type A and Type B uncertainties corrected for sample size using an appropriate Student t-factor.

Equipment used:

Instrument	Model number	Serial Number	NIST Certified CD/Recalibration	Resolution	Repeatability
FE-SEM	FEI Helios 600i	D9922192	CD-PG01-0211/June 2014	0.9nm	0.03%

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683-01 TN VUC-01 04292014